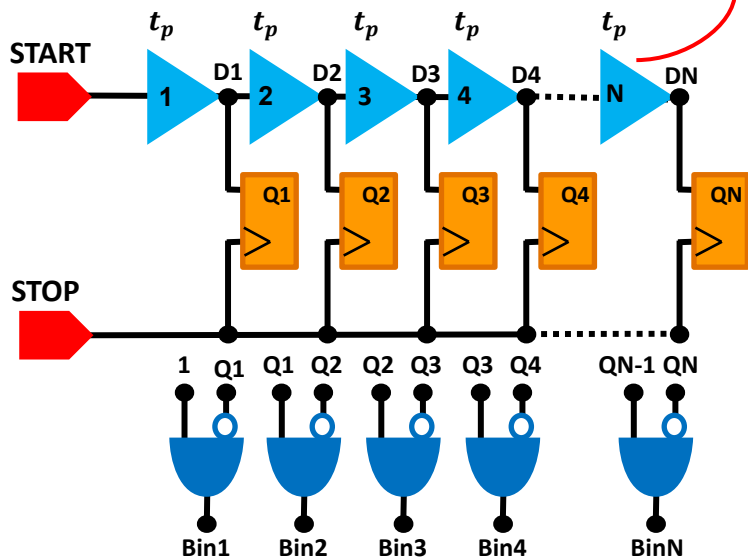


# Delay Line TDC

- Majority of modern TDCs is based on some version of a delay-line structure:



- TDC resolution given by the propagation delay of the elementary cell:

$$LSB_{TDC} = t_p$$

- Basic element: **Delay Cell**

- Simple Logic Cell:**
  - Used in FPGA TDCs
  - Requires constant calibration
- Digitally-Controlled Delay Cell:**
- Voltage-Controlled Delay Cell:**
  - Current starved:**

Delay controlled thru current
  - Shunt capacitor:**

Delay controlled thru load
- Differential delay cell with symmetric loads (Maneatis cell [1]):**
  - Frequently used in PLL VCOs and some DLLs
  - Consumes Static Bias Current

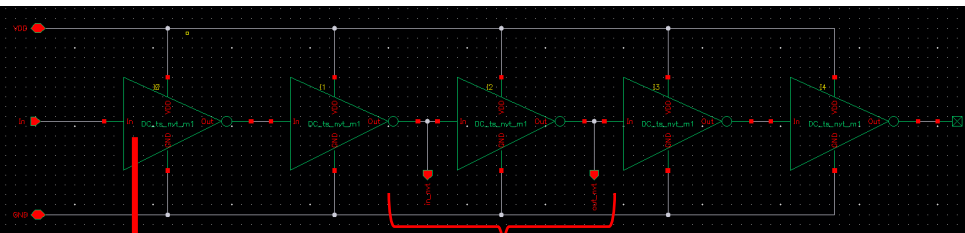
Minimum delay limited by fastest achievable logic propagation delay in target technology

[1] J. G. Maneatis, "Low-jitter process-independent DLL and PLL based on self-biased techniques," IEEE J. Solid-State Circuits, vol. 31, no. 11, pp. 1723–1732, Nov. 1996.

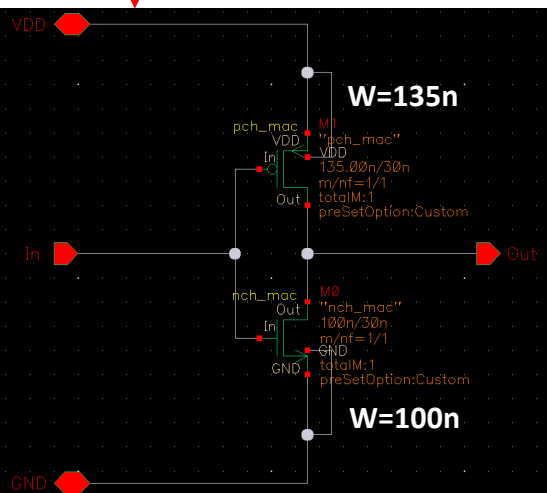


# Testbench

## Delay Line Test Structure:



$t_p$  - Cell Propagation Delay



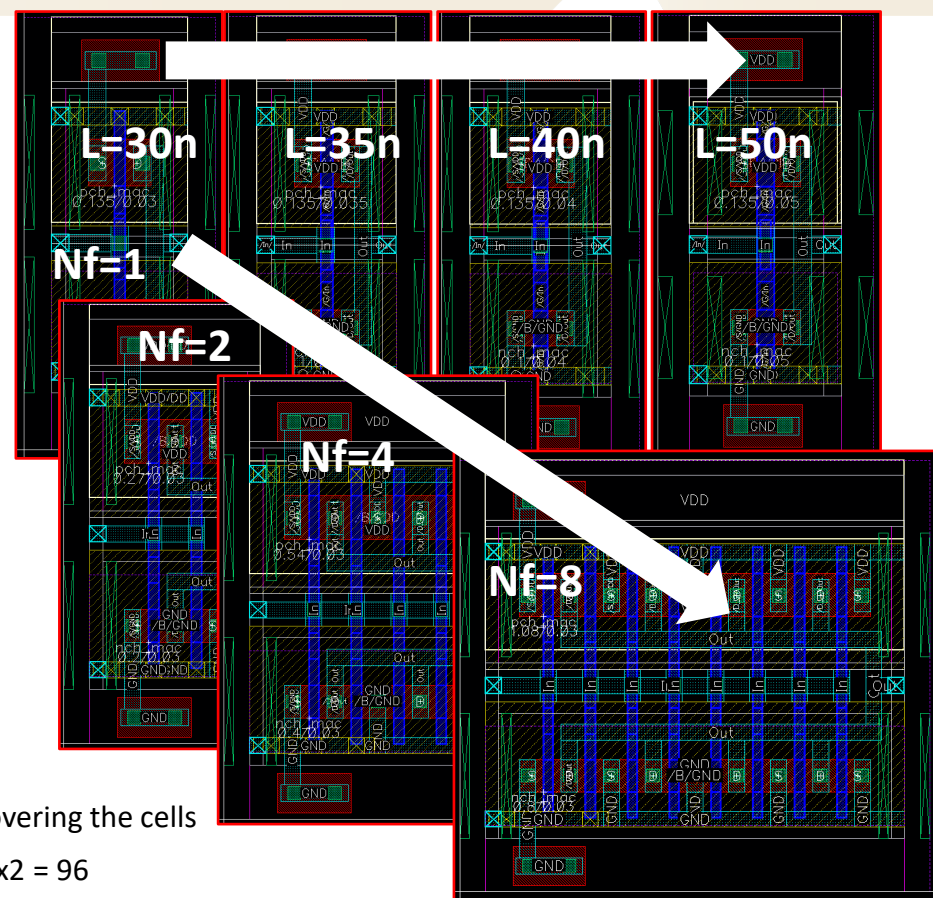
Simulations: Spectre

- **SCH** – Schematic
- **RCX** – Parasitic Extracted

Extraction: Calibre PEX

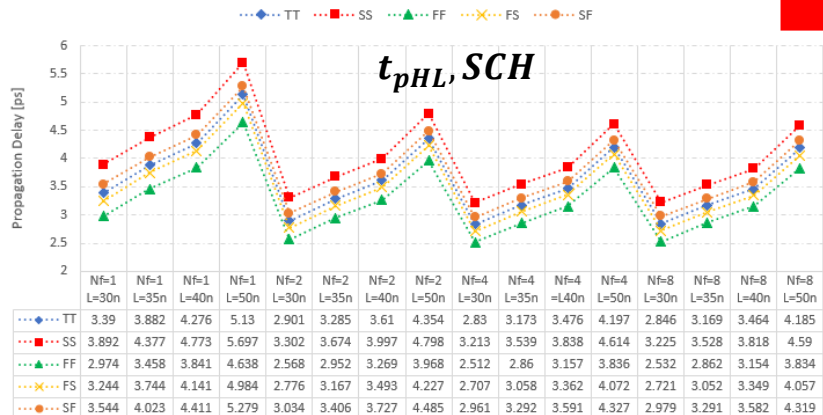
- M1 – Signal Connections
- M2 – VDD & GND planes covering the cells

Total Number of Views:  $4 \times 4 \times 3 \times 2 = 96$

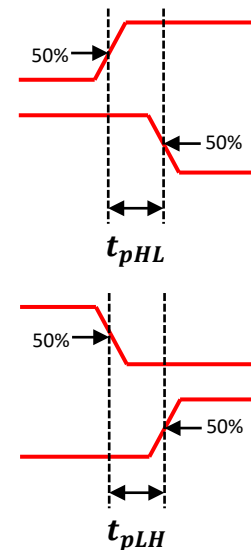
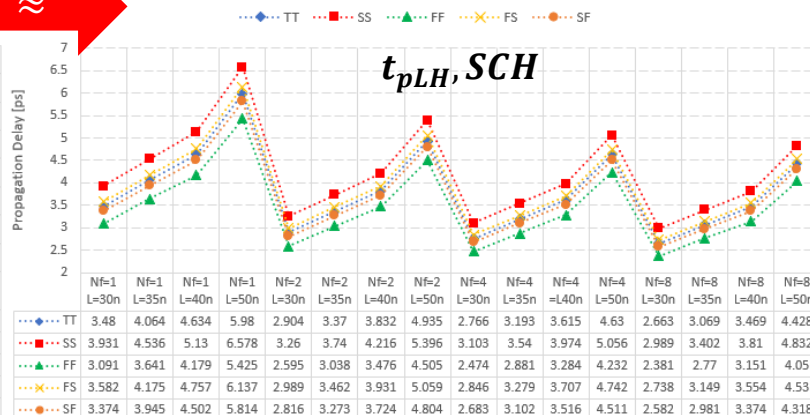


# SVT Propagation Delay: HL / LH VS Corners

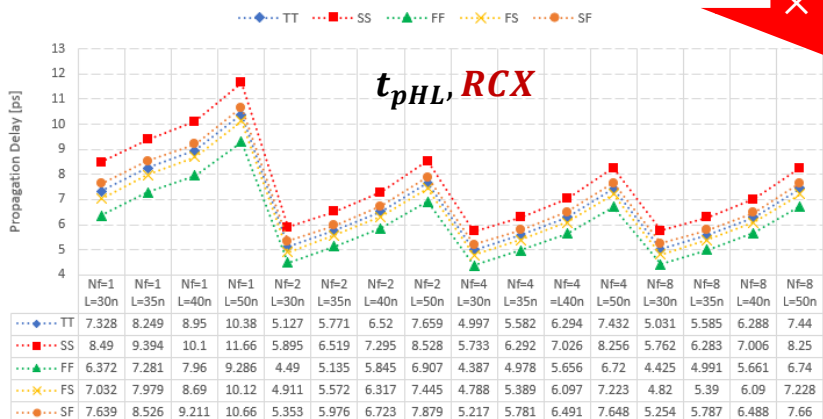
HL Delay VS Nf & L @SVT, VDD=0.9, temp=27 (SCH)



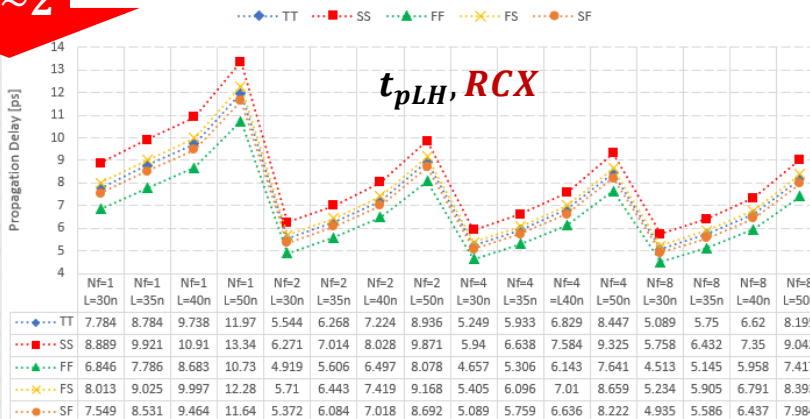
LH Delay VS Nf & L @SVT, VDD=0.9, temp=27 (SCH)



HL Delay VS Nf & L @SVT, VDD=0.9, temp=27 (RCX)



LH Delay VS Nf & L @SVT, VDD=0.9, temp=27 (RCX)

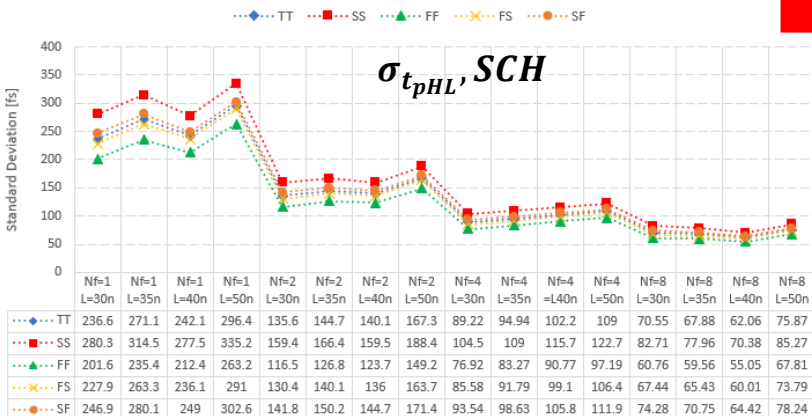


$t_{pSCH} \sim 3.5ps$

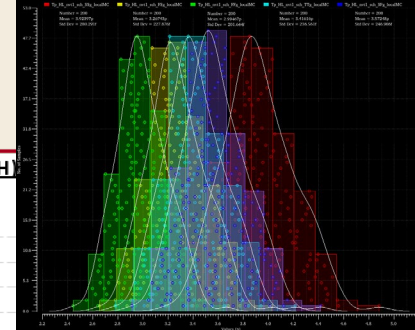
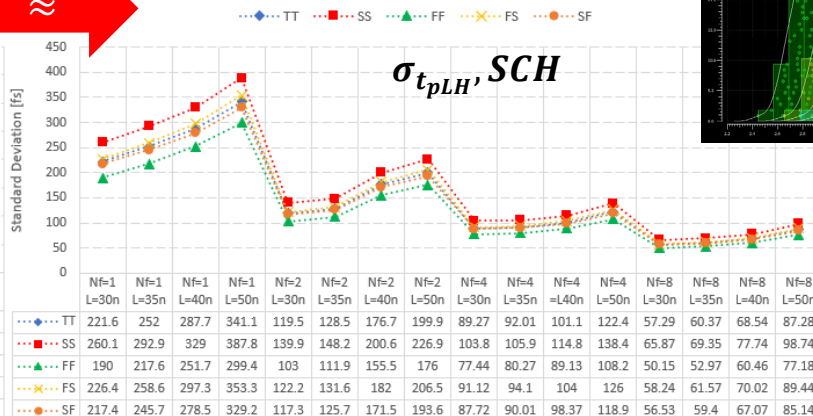
$t_{pRCX} \sim 7ps$

# SVT Propagation Delay – Monte Carlo: HL / LH

HL Delay Std VS Nf & L @SVT, VDD=0.9, temp=27 (SCH)



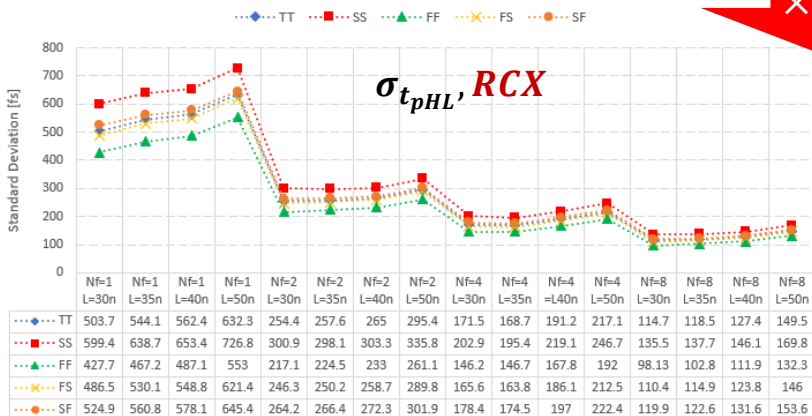
LH Delay Std VS Nf & L @SVT, VDD=0.9, temp=27 (SCH)



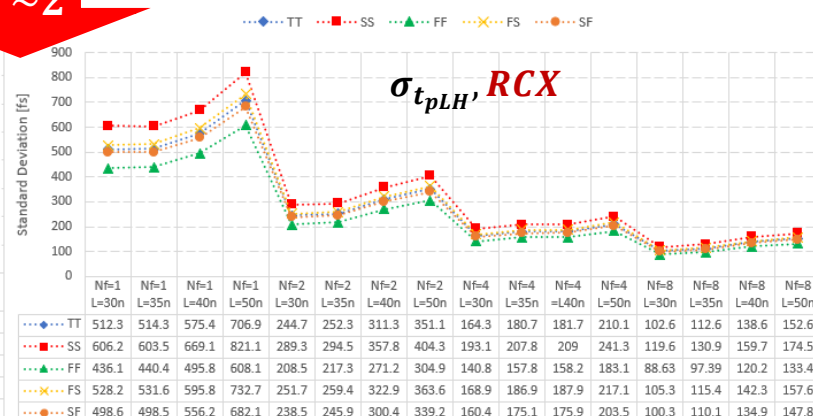
Settings:

- Global Corner + Local MC
- 5 corners:
  - TT, 0.9V, 27°C
  - SS, 0.9V, 27°C
  - FF, 0.9V, 27°C
  - FS, 0.9V, 27°C
  - SF, 0.9V, 27°C
- N° of runs per corner: 200

HL Delay Std VS Nf & L @SVT, VDD=0.9, temp=27 (RCX)



LH Delay Std VS Nf & L @SVT, VDD=0.9, temp=27 (RCX)



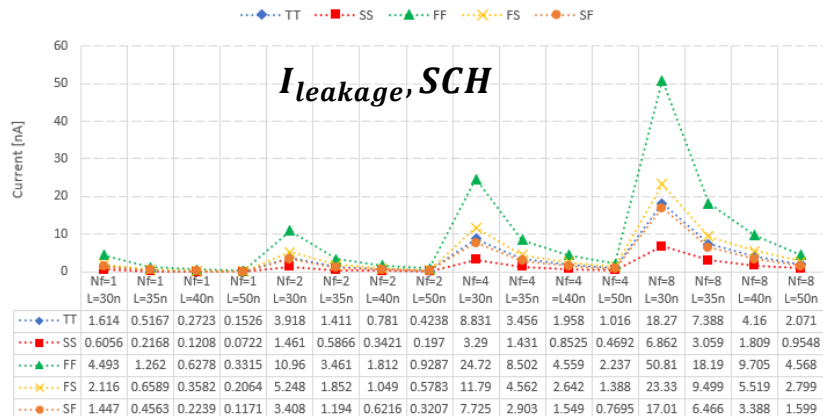
$\sigma_{t_{pSCH}} \sim 150fs$

$\sigma_{t_{pRCX}} \sim 300fs$

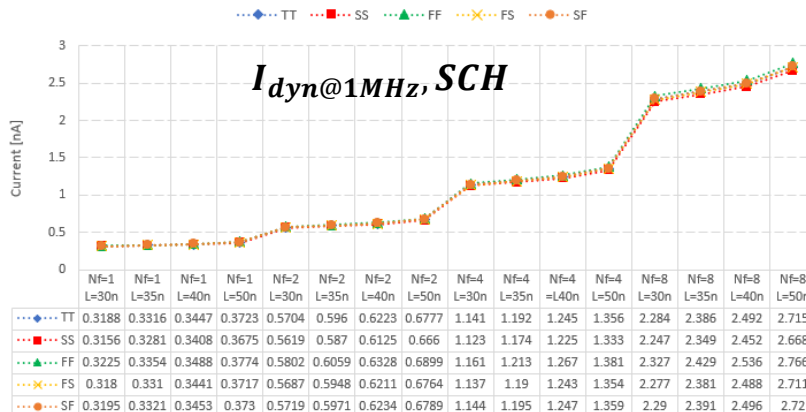
# SVT Current Consumption: Leakage / Dynamic@1MHz

TID-ID  

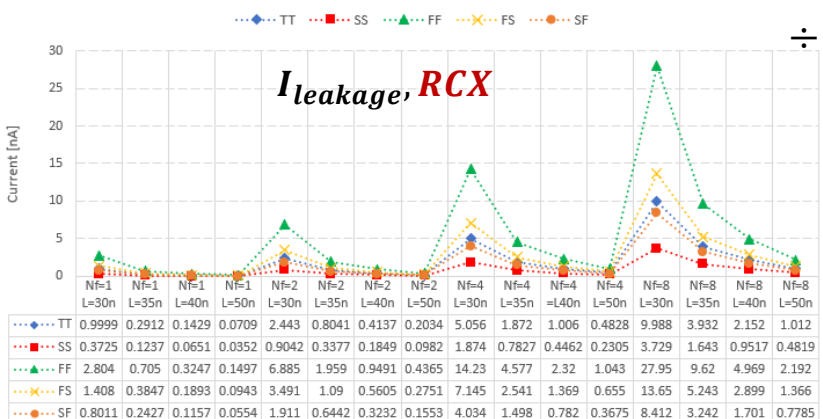
Leakage I VS Nf & L @SVT, VDD=0.9, temp=27 (SCH)



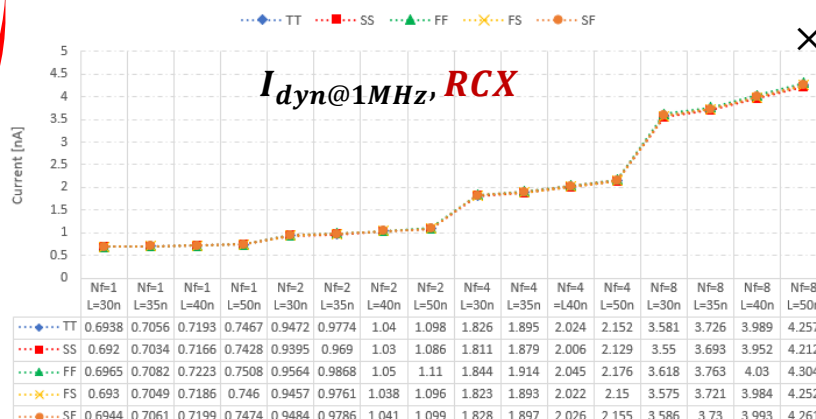
Dynamic I @ 1MHz VS Nf & L @SVT, VDD=0.9, temp=27 (SCH)



Leakage I VS Nf & L @SVT, VDD=0.9, temp=27 (RCX)



Dynamic I @ 1MHz VS Nf & L @SVT, VDD=0.9, temp=27 (RCX)

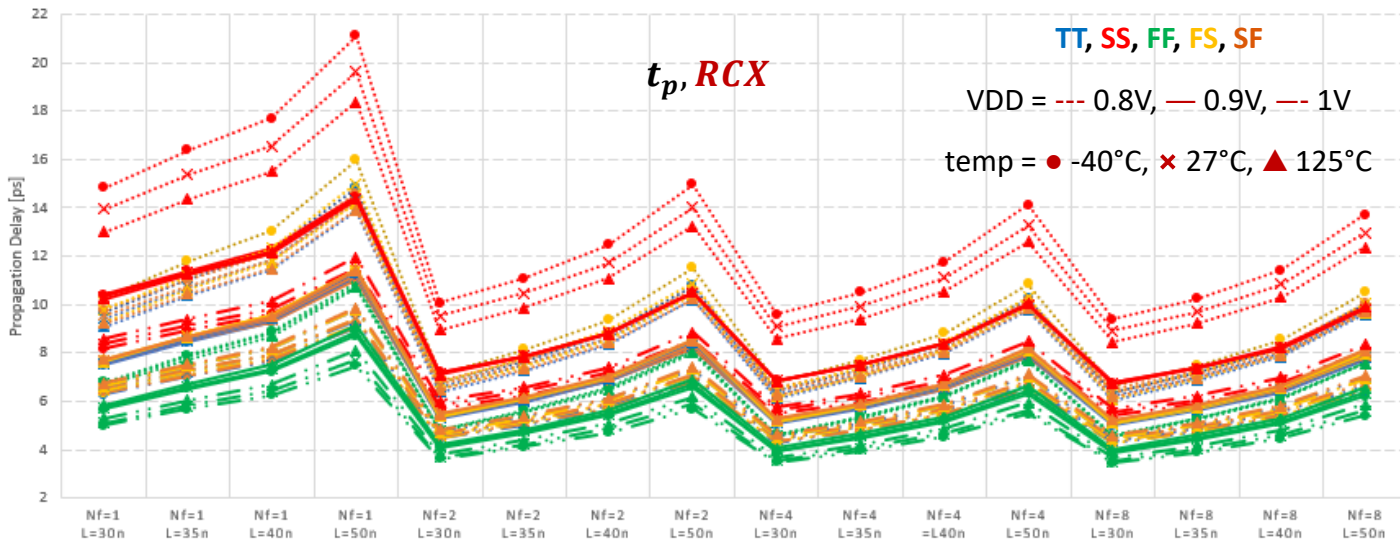


÷ ~1.6  
÷ ~2.1

× ~2.1  
× ~1.6

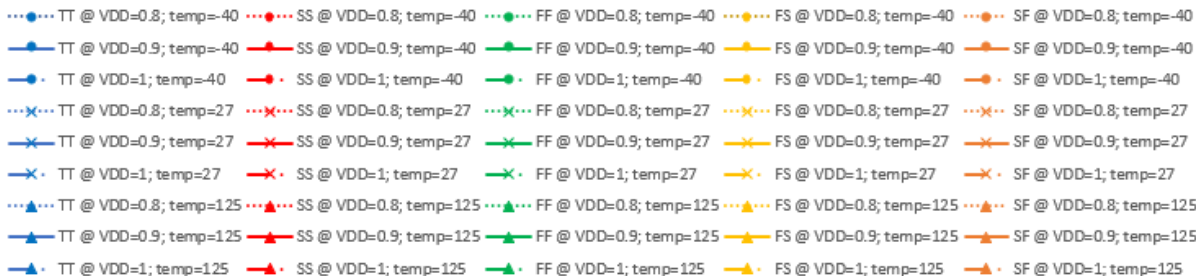
# SVT Propagation Delay VS corners, VDD, temp

Delay VS Nf & L @SVT (RCX)



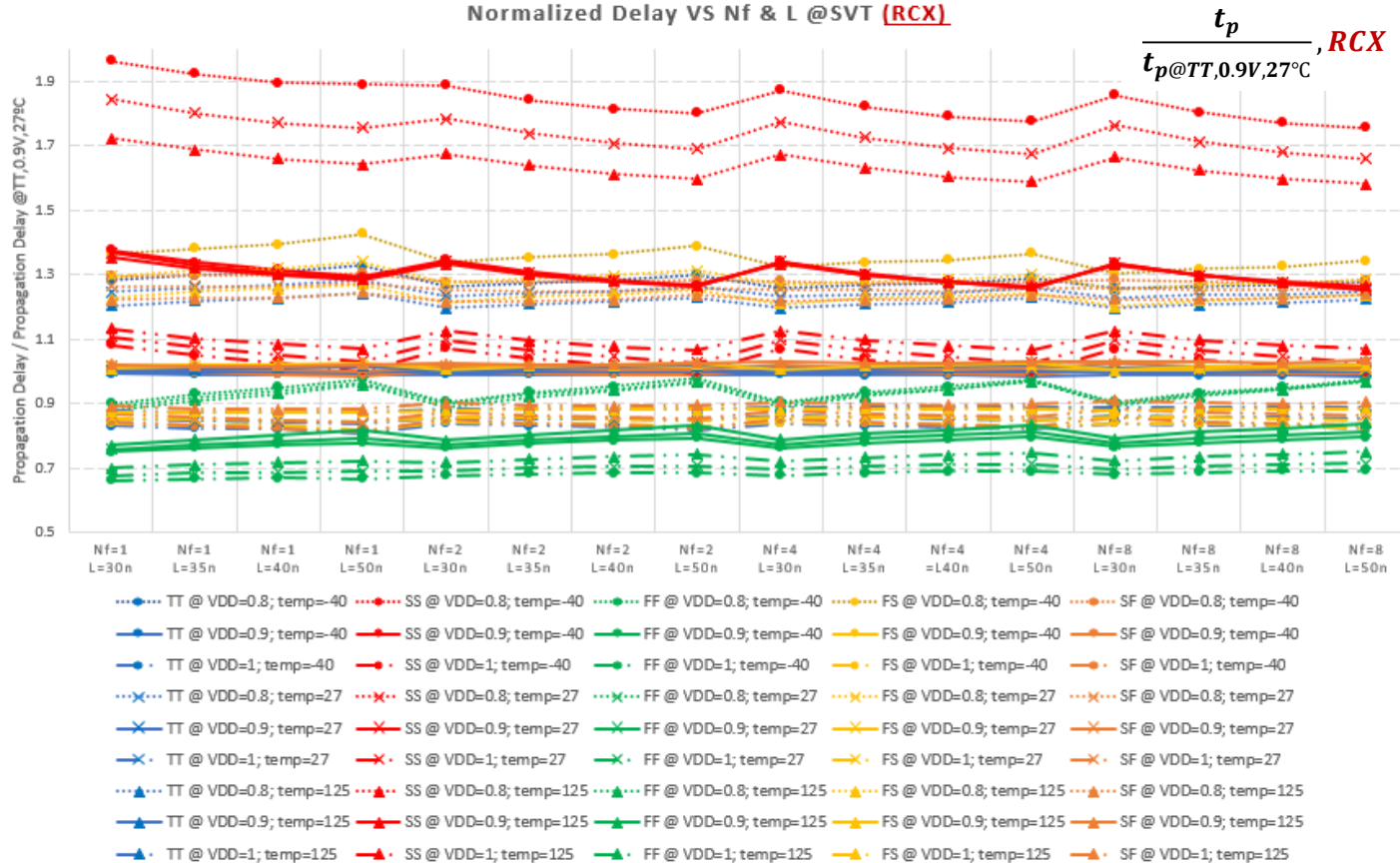
$$t_p = \frac{t_{pHL} + t_{pLH}}{2}$$

- Best Case (Fastest):  
FF @ VDD=1V & -40°C
- Worst Case (Slowest):  
SS @ VDD=0.8V & -40°C



# SVT Propagation Delay VS corners, VDD, temp

Normalized Delay VS Nf & L @SVT (RCX)



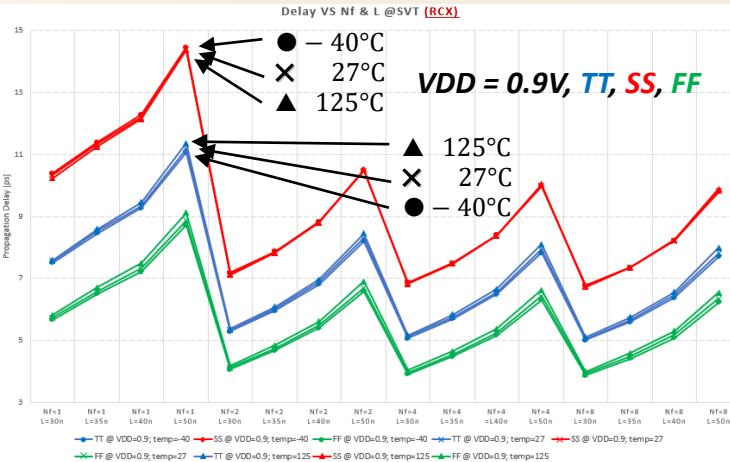
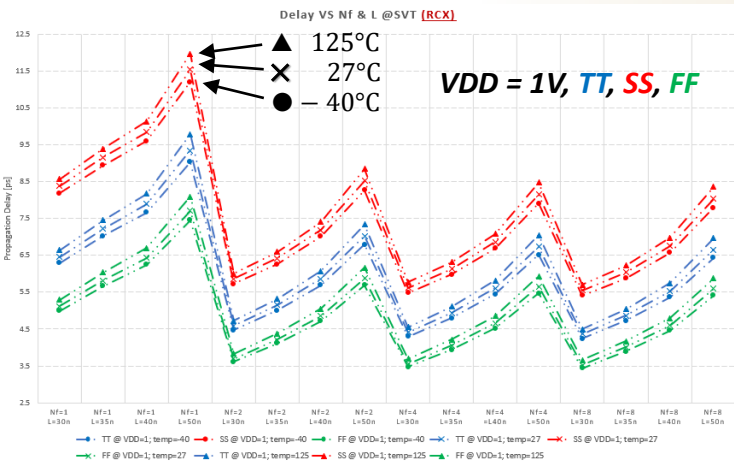
$$t_p = \frac{t_{pHL} + t_{pLH}}{2}$$

- Best Case (Fastest):  
FF @ VDD=1V & -40°C
- Worst Case (Slowest):  
SS @ VDD=0.8V & -40°C

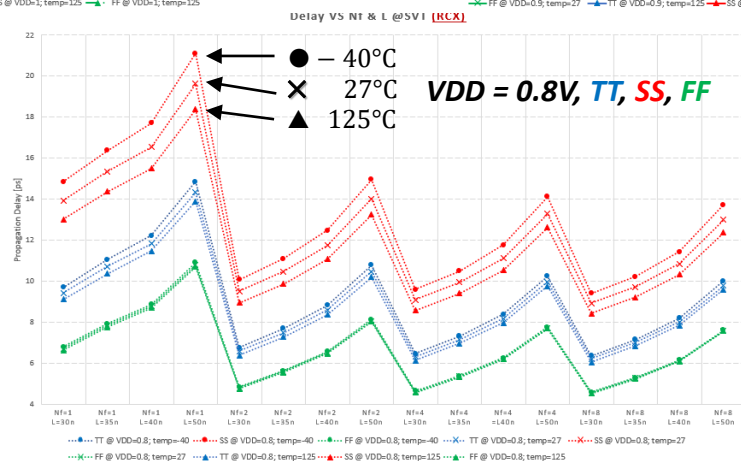
$$\frac{WorstCase}{Typical} \sim 1.9$$

$$\frac{BestCase}{Typical} \sim 0.68$$

# SVT Propagation Delay VS corners, VDD, temp



- Very small variation with temperature (especially at VDD=0.9V)
- At VDD = 0.8V, the delay is higher for lower temperatures (?)

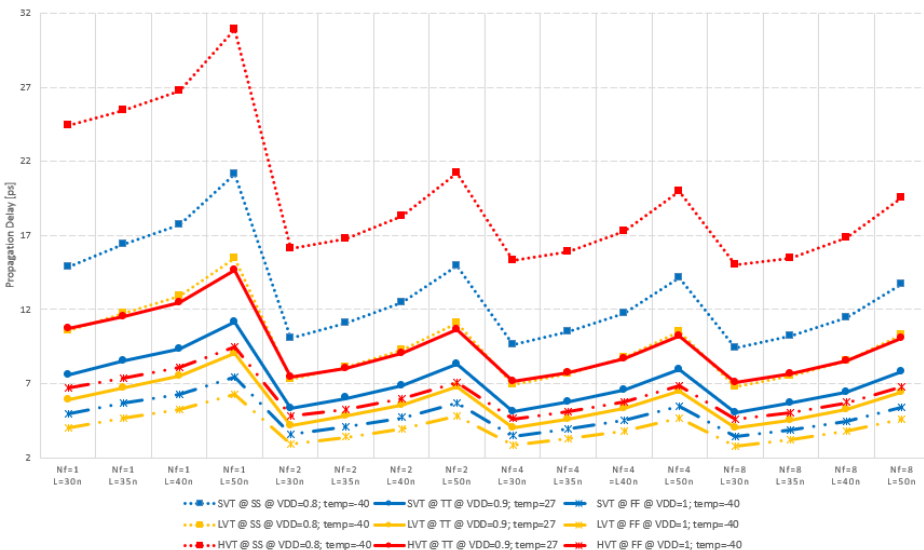


# Propagation Delay: SVT, LVT, HVT

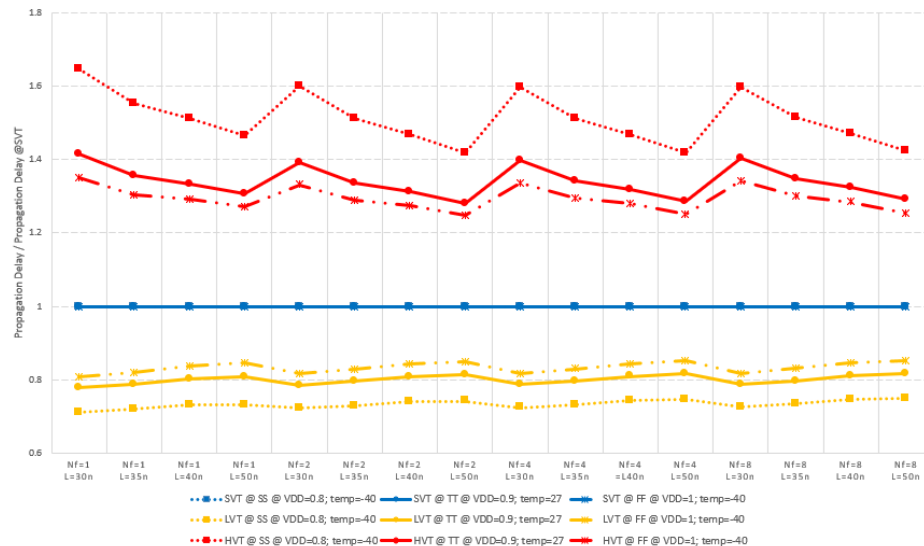
$$t_p, RCX$$

$$\frac{t_p}{t_{p@SVT}}, RCX$$

Delay VS Nf & L (RCX)



Normalized Delay VS Nf & L (RCX)

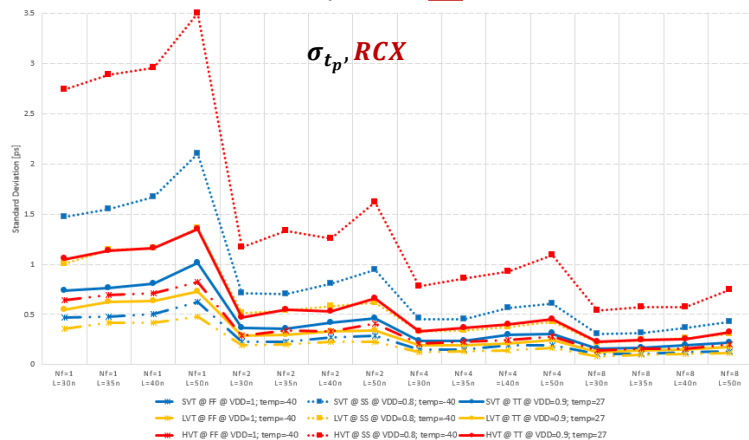


**SVT**  
**LVT**  
**HVT**

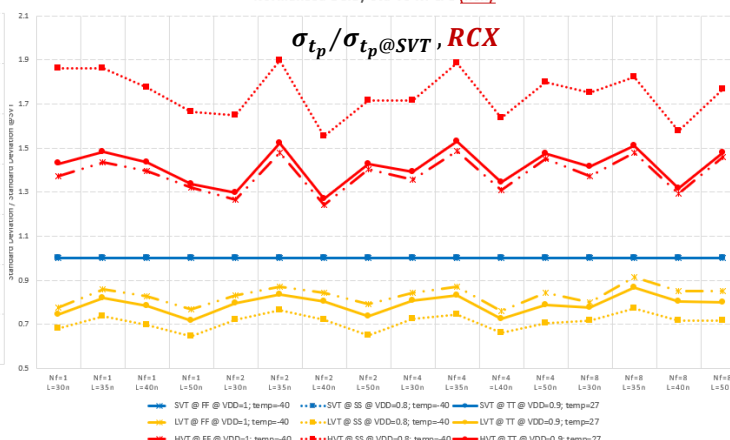
---■ SS; VDD = 0.8V; temp = -40°C  
—● TT; VDD = 0.9V; temp = 27°C  
---× FF; VDD = 1V; temp = -40°C

# Propagation Delay – Monte Carlo: SVT, LVT, HVT

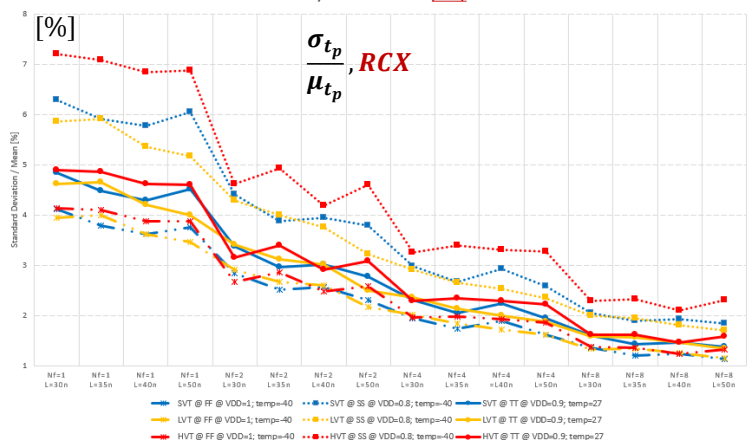
Delay Std VS Nf & L (RCX)



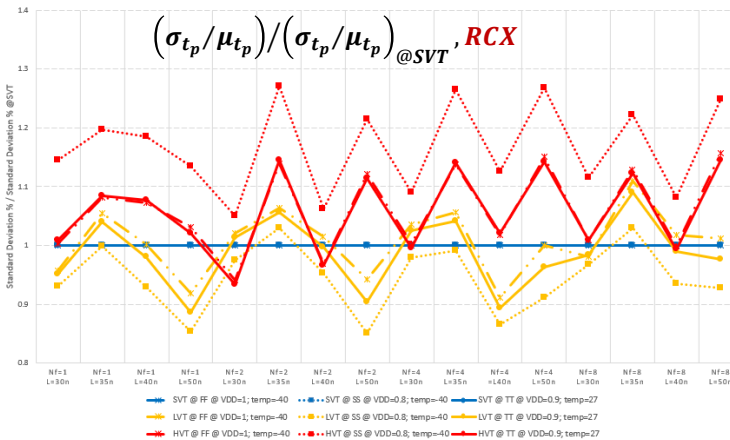
Normalized Delay Std VS Nf & L (RCX)



Delay Std % VS Nf & L (RCX)



Normalized Delay Std % VS Nf & L (RCX)



Settings:

- Global Corner + Local MC
- 5 corners:
  - TT, 0.9V, 27°C
  - SS, 0.8V, -40°C
  - FF, 1V, -40°C
- N° of runs per corner: 500

$$\sigma_{t_p} = \sqrt{\sigma_{t_{pHL}}^2 + \sigma_{t_{pLH}}^2}$$

- $\frac{\sigma_{t_p}}{\mu_{t_p}}$  similar (+27%, -15%) for SVT, LVT and HVT structures

SVT  
LVT  
HVT

---■ SS; VDD = 0.8V; T = -40°C  
 —● TT; VDD = 0.9V; T = 27°C  
 ---× FF; VDD = 1V; T = -40°C

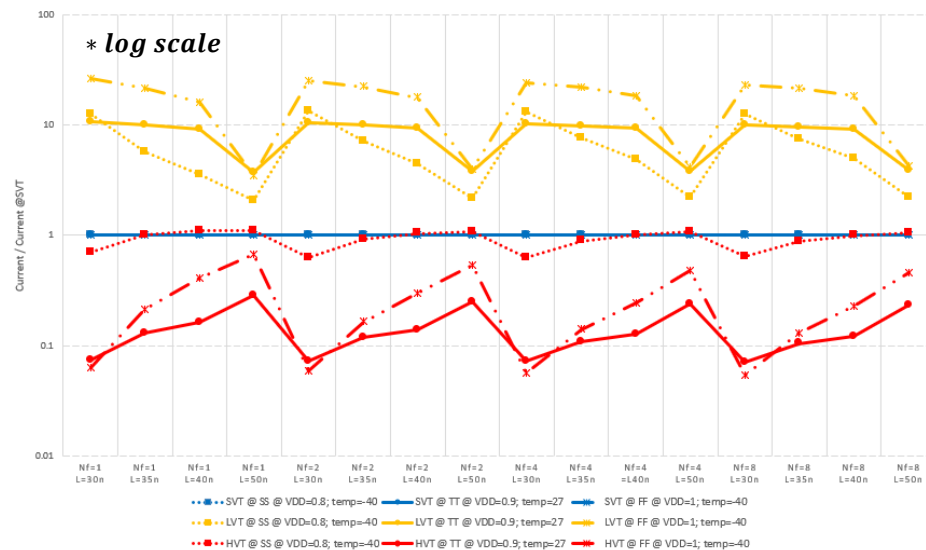
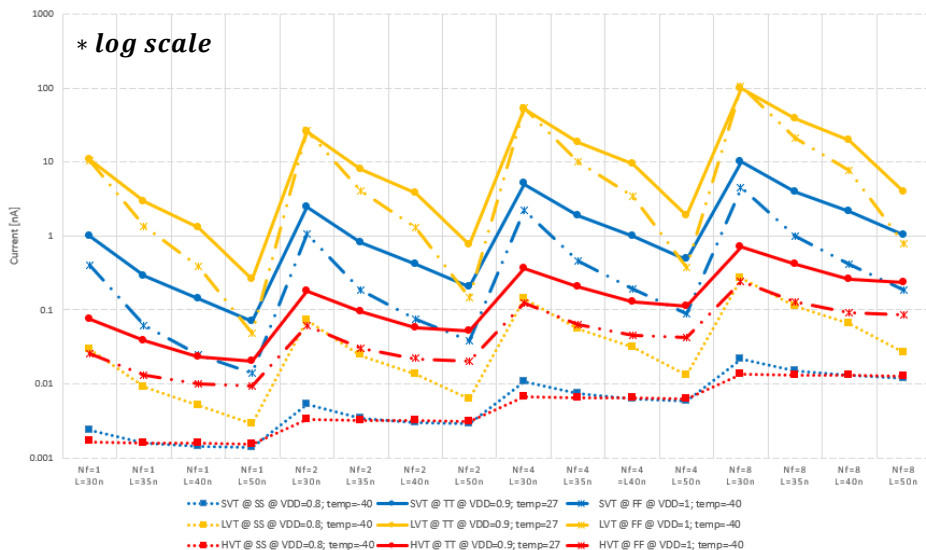
# Leakage Current: SVT, LVT, HVT

$I_{leakage}$ , **RCX**

$$\frac{I_{leakage}}{I_{leakage@SVT}}, \text{RCX}$$

Leakage I VS Nf & L (RCX)

Normalized Leakage I VS Nf & L (RCX)



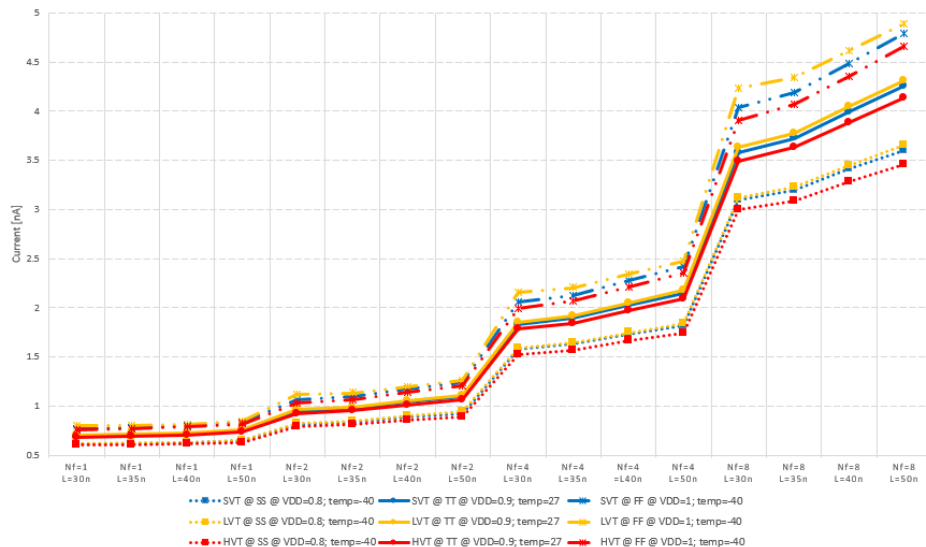
**SVT**  
**LVT**  
**HVT**

---■ SS; VDD = 0.8V; temp = -40°C  
 —● TT; VDD = 0.9V; temp = 27°C  
 ---× FF; VDD = 1V; temp = -40°C

# Dynamic Current @1MHz: SVT, LVT, HVT

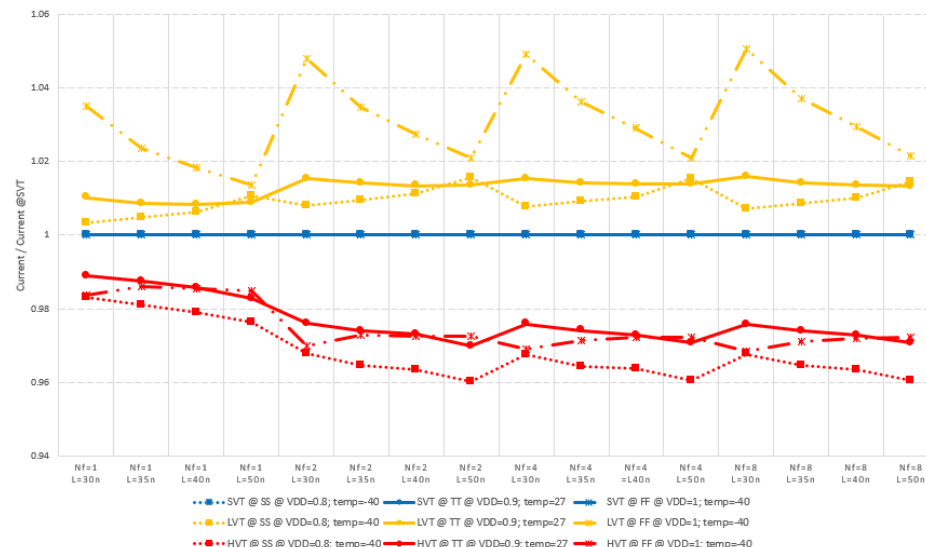
$$I_{dyn@1MHz}, RCX$$

Dynamic I VS Nf & L (RCX)



$$\frac{I_{dyn@1MHz}}{I_{dyn@1MHz@SVT}}, RCX$$

Normalized Dynamic I VS Nf & L (RCX)

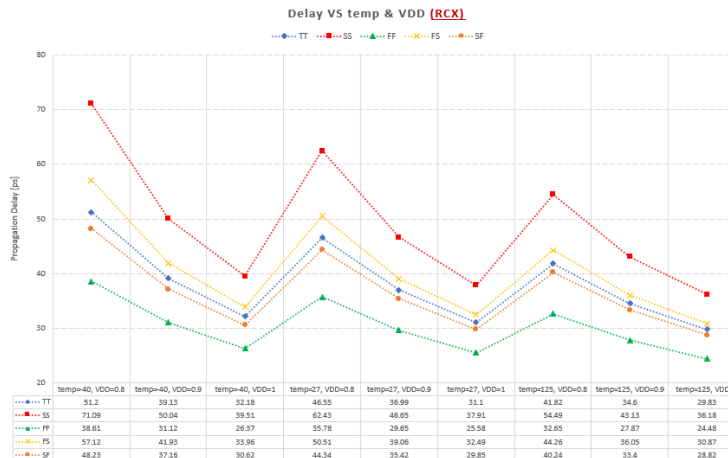
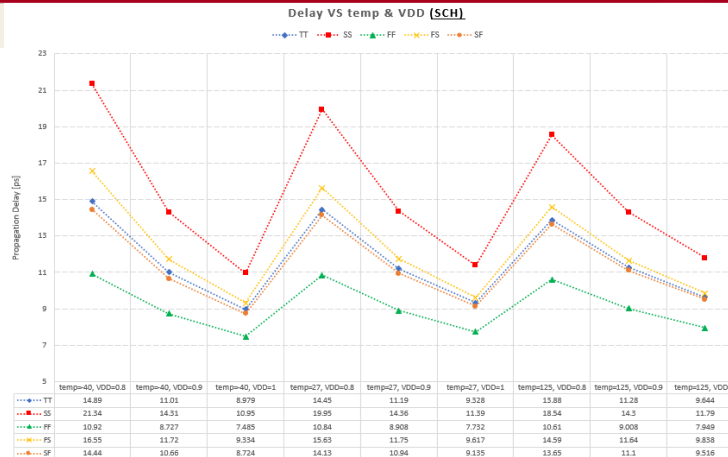
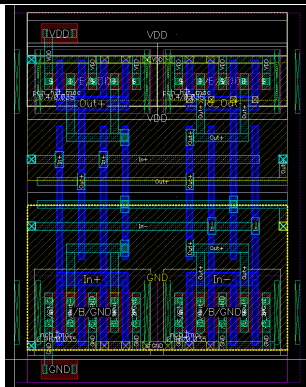
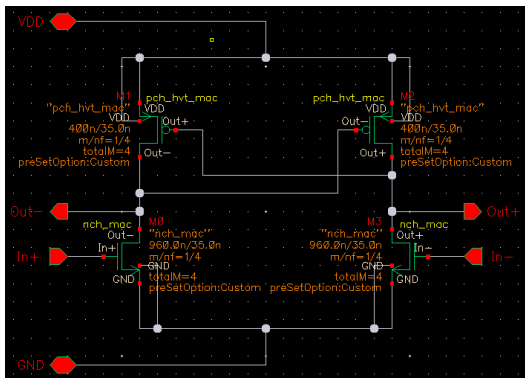


**SVT**    ---■ SS; VDD = 0.8V; temp = -40°C  
**LVT**    —● TT; VDD = 0.9V; temp = 27°C  
**HVT**    ---× FF; VDD = 1V; temp = -40°C

- Dynamic consumption very similar (+5%, -4%) for SVT, LVT and HVT structures

# DCVSL Delay Cell

## □ Differential Cascode Voltage Switch Logic (DCVSL) Implementation:



× ~3.5

